

**Search Notes**

Application/Control No.

10/816,696

Examiner

Biju Chandran

Applicant(s)/Patent under  
Reexamination

LAM, AN HIEN

Art Unit

2835

**SEARCHED**

Class	Subclass	Date	Examiner
361	676	11/21/2005	BIC
361	678	11/21/2005	BIC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
see search history		